



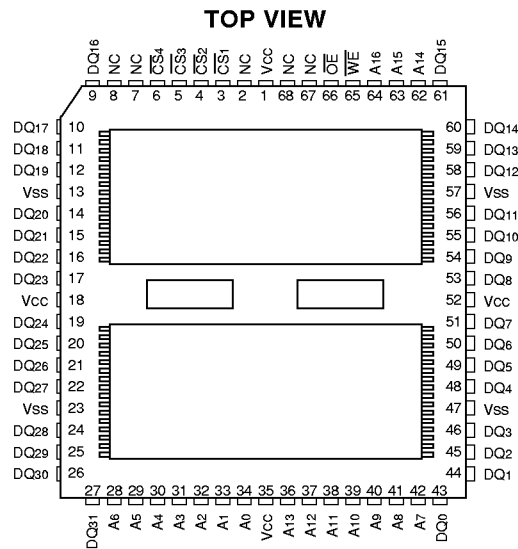
128Kx32 5V FLASH MODULE PRELIMINARY*

FEATURES

- Maximum Access Time of 55ns
- Packaging
 - 68 Lead, Plastic PLCC, 24.94 mm (0.982 inch) square
- Sector Architecture
 - 8 equal size sectors of 16KBytes each
 - Any combination of sectors can be concurrently erased. Also supports full chip erase
- Minimum 100,000 Write/Erase Cycles
- Organized as 128Kx32
- Commercial and Industrial Temperature Ranges
- 5 Volt Programming. 5V ±10% Supply
- Low Power CMOS, 500µA Standby Typical
- Embedded Erase and Program Algorithms
- TTL Compatible Inputs and CMOS Outputs
- Page Program Operation and Internal Program Control Time
- Built-in Decoupling Caps for Low Noise Operation

** This data sheet describes a product under development, not fully characterized, and is subject to change without notice.*

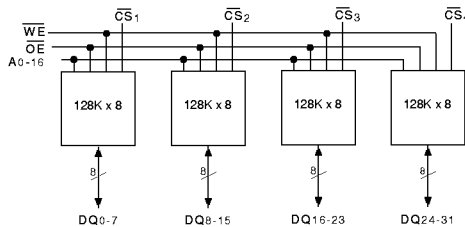
FIG. 1 PIN CONFIGURATION FOR WPF128K32-55PJX5



PIN DESCRIPTION

DQ0-31	Data Inputs/Outputs
A0-16	Address Inputs
\overline{WE}	Write Enable
\overline{CS}_{1-4}	Chip Selects
\overline{OE}	Output Enable
Vcc	Power Supply
Vss	Ground
NC	Not Connected

BLOCK DIAGRAM





ABSOLUTE MAXIMUM RATINGS

Parameter		Unit
Operating Temperature (Com)	0 to +70	°C
Operating Temperature (Ind.)	-40 to +85	°C
Supply Voltage Range (Vcc)	-2.0 to +7.0	V
Signal Voltage Range (any pin except A9) (2)	-2.0 to +7.0	V
Storage Temperature Range	-55 to +125	°C
Data Retention	10 years	
Endurance (write/erase cycles)	100,000 cycles min.	
A9 Voltage for Sector Protect (Vid) (3)	-2.0 to +14.0	V

NOTES:

- Stresses above the absolute maximum rating may cause permanent damage to the device. Extended operation at the maximum levels may degrade performance and affect reliability.
- Minimum DC voltage on input or DQ pins is -0.5V. During voltage transitions, inputs may overshoot Vss to -2.0 V for periods of up to 20ns. Maximum DC voltage on output and DQ pins is Vcc + 0.5V. During voltage transitions, outputs may overshoot to Vcc + 2.0 V for periods of up to 20ns.
- Minimum DC input voltage on A9 pin is -0.5V. During voltage transitions, A9 may overshoot Vss to -2V for periods of up to 20ns. Maximum DC input voltage on A9 is +13.5V which may overshoot to 14.0 V for periods up to 20ns.
- Recommended soldering temperature not to exceed 215°C for 20 seconds.**

RECOMMENDED OPERATING CONDITIONS

Parameter	Symbol	Min	Max	Unit
Supply Voltage	Vcc	4.5	5.5	V
Input High Voltage	V _{IH}	2.0	Vcc + 0.3	V
Input Low Voltage	V _{IL}	-0.5	+0.8	V
Operating Temp. (Com)	T _A	0	+70	°C
Operating Temp. (Ind)	T _A	-40	+85	°C
A9 Voltage for sector Protect	V _{id}	11.5	12.5	V

CAPACITANCE

(T_A = +25°C)

Parameter	Symbol	Conditions	Max	Unit
\overline{OE} capacitance	C _{oE}	V _{IN} = 0 V, f = 1.0 MHz	35	pF
\overline{WE} capacitance	C _{wE}	V _{IN} = 0 V, f = 1.0 MHz	30	pF
\overline{CS} 1-4 capacitance	C _{cs}	V _{IN} = 0 V, f = 1.0 MHz	12	pF
Data I/O capacitance	C _{I/O}	V _{I/O} = 0 V, f = 1.0 MHz	12	pF
Address input capacitance	C _{AD}	V _{IN} = 0 V, f = 1.0 MHz	35	pF

This parameter is guaranteed by design but not tested.

DC CHARACTERISTICS - CMOS COMPATIBLE

(Vcc = 5.0V, Vss = 0V, T_A = -40°C to +85°C)

Parameter	Symbol	Conditions	-55		Unit
			Min	Max	
Input Leakage Current	I _{LI}	Vcc = 5.5, V _{IN} = Vss to Vcc		10	μA
Output Leakage Current	I _{LOx2}	Vcc = 5.5, V _{IN} = Vss to Vcc		10	μA
Vcc Active Current for Read (1)	I _{CC1}	$\overline{CS} = V_{IL}, \overline{OE} = V_{IH}$		120	mA
Vcc Active Current for Program or Erase (2)	I _{CC2}	$\overline{CS} = V_{IL}, \overline{OE} = V_{IH}$		200	mA
Vcc Standby Current	I _{CC3}	Vcc = 5.5, $\overline{CS} = V_{IH}, f = 5\text{MHz}$		500	μA
Output Low Voltage	V _{OL}	I _{OL} = 12.0 mA, Vcc = 4.5		0.45	V
Output High Voltage	V _{OH1}	I _{OH} = -2.5 mA, Vcc = 4.5	0.85 x Vcc		V
Output High Voltage	V _{OH2}	I _{OH} = -100 μA, Vcc = 4.5	Vcc -0.4		V
Low Vcc Lock Out Voltage	V _{LKO}		3.2		V

NOTES:

- The I_{CC} current listed includes both the DC operating current and the frequency dependent component (at 5 MHz). The frequency component typically is less than 2 mA/MHz, with \overline{OE} at V_{IH}.
- I_{CC} active while Embedded Algorithm (program or erase) is in progress.
- DC test conditions: V_{IL} = 0.3V, V_{IH} = Vcc - 0.3V

**AC CHARACTERISTICS – WRITE/ERASE/PROGRAM OPERATIONS, \overline{WE} CONTROLLED**

(Vcc = 5.0V, Vss = 0V, TA = -40°C to +85°C)

Parameter	Symbol		-55		Unit
			Min	Max	
Write Cycle Time (1)	tAVAV	tWC	55		ns
Chip Select Setup Time	tELWL	tCS	0		ns
Write Enable Pulse Width	tWLWH	tWP	30		ns
Address Setup Time	tAVWL	tAS	0		ns
Data Setup Time	tDVWH	tDS	20		ns
Data Hold Time	tWHDX	tDH	0		ns
Address Hold Time	tWLAX	tAH	45		ns
Chip Select Hold Time	tWHEH	tCH	0		ns
Write Enable Pulse Width High (1)	tWHWL	tWPH	20		ns
Duration of Byte Programming Operation	tWHWH1		14		μs
Sector Erase Time	tWHWH2		2.2	30	sec
Read Recovery Time Before Write (1)	tGHWL		0		μs
Vcc Setup Time (1)		tVCS	50		μs
Chip Programming Time				12.5	sec
Output Enable Setup Time		tOES	0		ns
Output Enable Hold Time (2)		tOEH	10		ns
Chip Erase Time				120	sec

1. Guaranteed by design but not tested.

2. For Toggle and Data Polling.

AC CHARACTERISTICS – WRITE/ERASE/PROGRAM OPERATIONS, \overline{CS} CONTROLLED

(Vcc = 5.0V, Vss = 0V, TA = -40°C to +85°C)

Parameter	Symbol		-55		Unit
			Min	Max	
Write Cycle Time (1)	tAVAV	tWC	55		ns
\overline{WE} Setup Time	tWLLEL	tWS	0		ns
\overline{CS} Pulse Width	tELEH	tCP	30		ns
Address Setup Time	tAVEL	tAS	0		ns
Data Setup Time	tDVEH	tDS	20		ns
Data Hold Time	tEHDX	tDH	0		ns
Address Hold Time	tELAX	tAH	45		ns
\overline{WE} Hold from \overline{WE} High	tEHHH	tWH	0		ns
\overline{CS} Pulse Width High	tEHEL	tCPH	20		ns
Duration of Programming Operation	tWHWH1		14		μs
Sector Erase Operation	tWHWH2		2.2	30	sec
Read Recovery Before Write	tGHLEL		0		ns
Chip Programming Time				12.5	sec
Chip Erase Time				120	sec

1. Guaranteed by design but not tested.



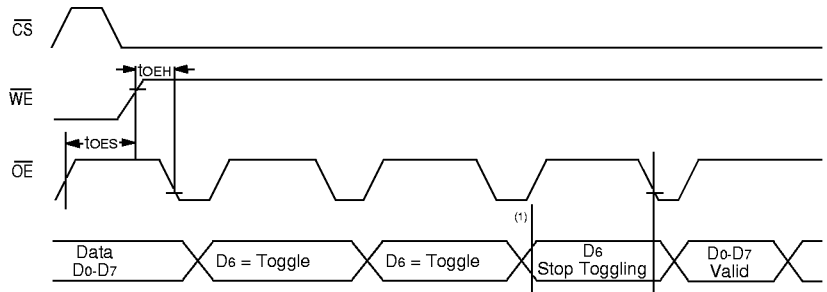
AC CHARACTERISTICS – READ ONLY OPERATIONS

(Vcc = 5.0V, Vss = 0V, TA = -40°C to +85°C)

Parameter	Symbol		-55		Unit
			Min	Max	
Read Cycle Time	tAVAV	tRC	55		ns
Address Access Time	tAVQV	tACC		55	ns
Chip Select Access Time	tELQV	tCE		55	ns
\overline{OE} to Output Valid	tGLQV	tOE		30	ns
Chip Select to Output High Z (1)	tEHQZ	tDF		15	ns
\overline{OE} High to Output High Z (1)	tGHQZ	tDF		15	ns
Output Hold from Address, \overline{CS} or \overline{OE} Change, whichever is first	tAXQX	tOH	0		ns

1. Guaranteed by design, not tested.

FIG. 2
AC WAVEFORMS FOR
TOGGLE BIT DURING
EMBEDDED ALGORITHM
OPERATIONS



NOTES:

1. D6 stops toggling (the device has completed the Embedded operation).



FIG. 3
AC WAVEFORMS FOR READ OPERATIONS

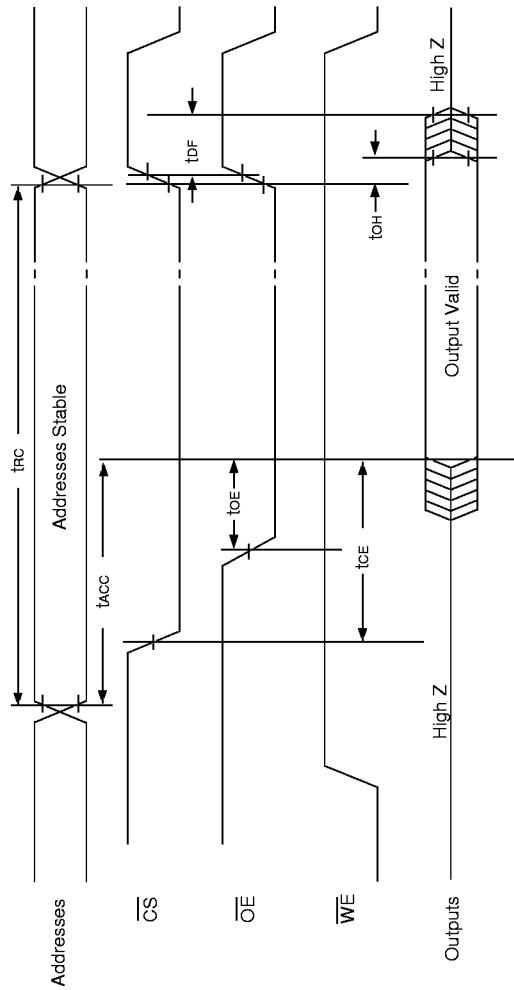
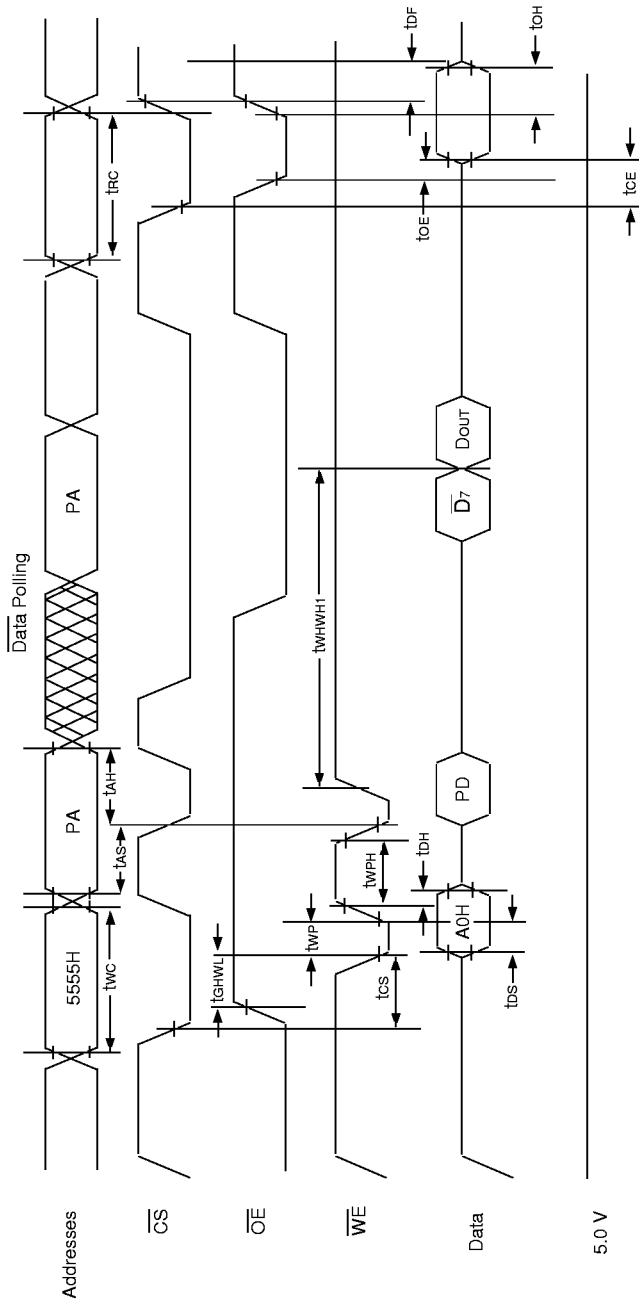




FIG. 4
WRITE/ERASE/PROGRAM OPERATION, WE CONTROLLED

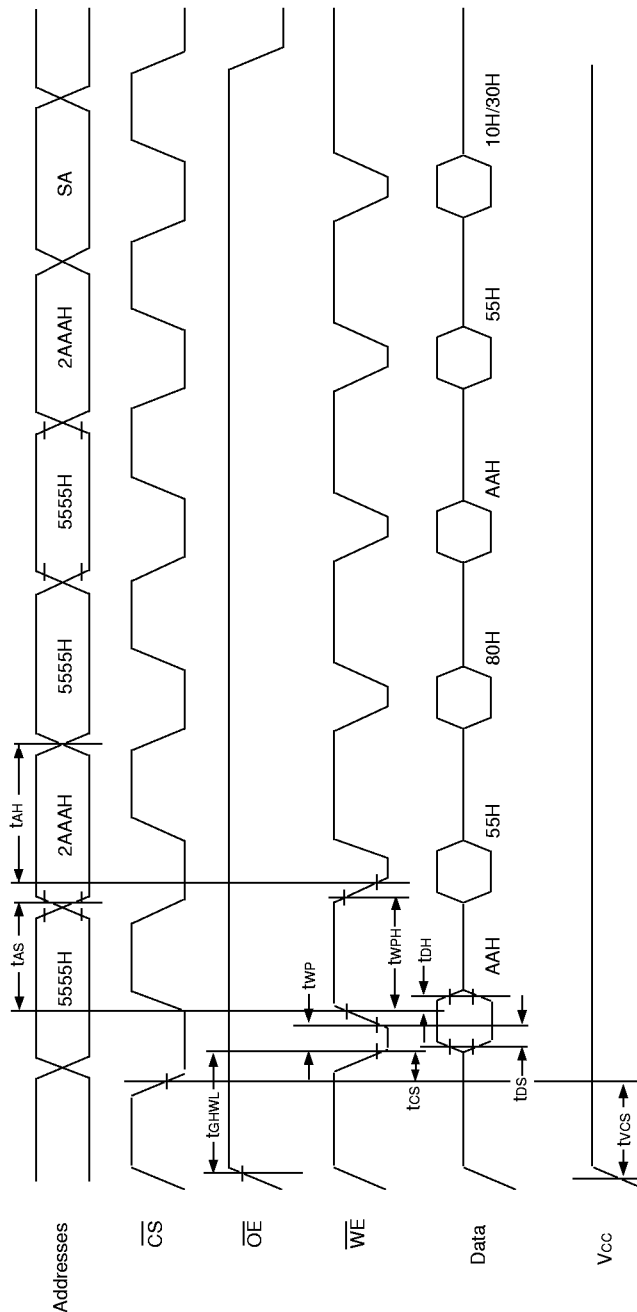


NOTES:

1. PA is the address of the memory location to be programmed.
2. PD is the data to be programmed at byte address.
3. $\overline{D7}$ is the output of the complement of the data written to the device.
4. DOUT is the output of the data written to the device.
5. Figure indicates last two bus cycles of four bus cycle sequence.



FIG. 5
AC WAVEFORMS CHIP/SECTOR ERASE OPERATIONS



NOTES:
1. SA is the sector address for sector Erase.



FIG. 6
AC WAVEFORMS FOR DATA POLLING DURING
EMBEDDED ALGORITHM OPERATIONS

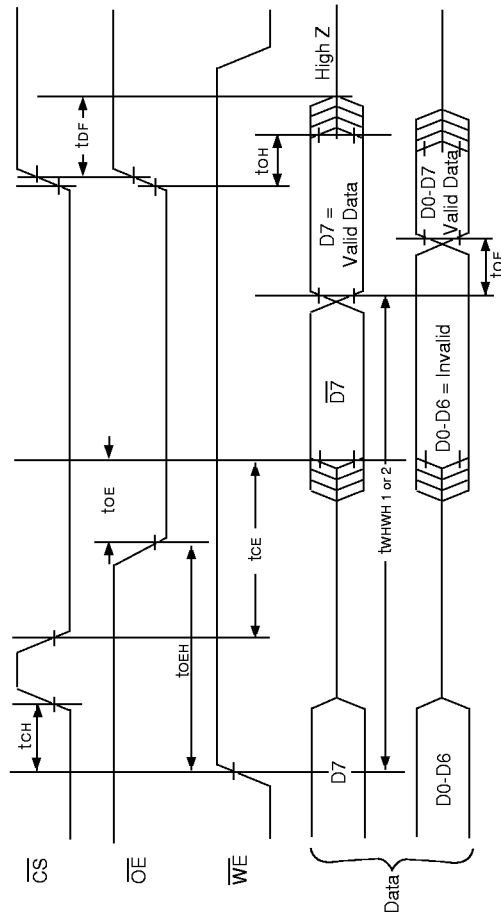
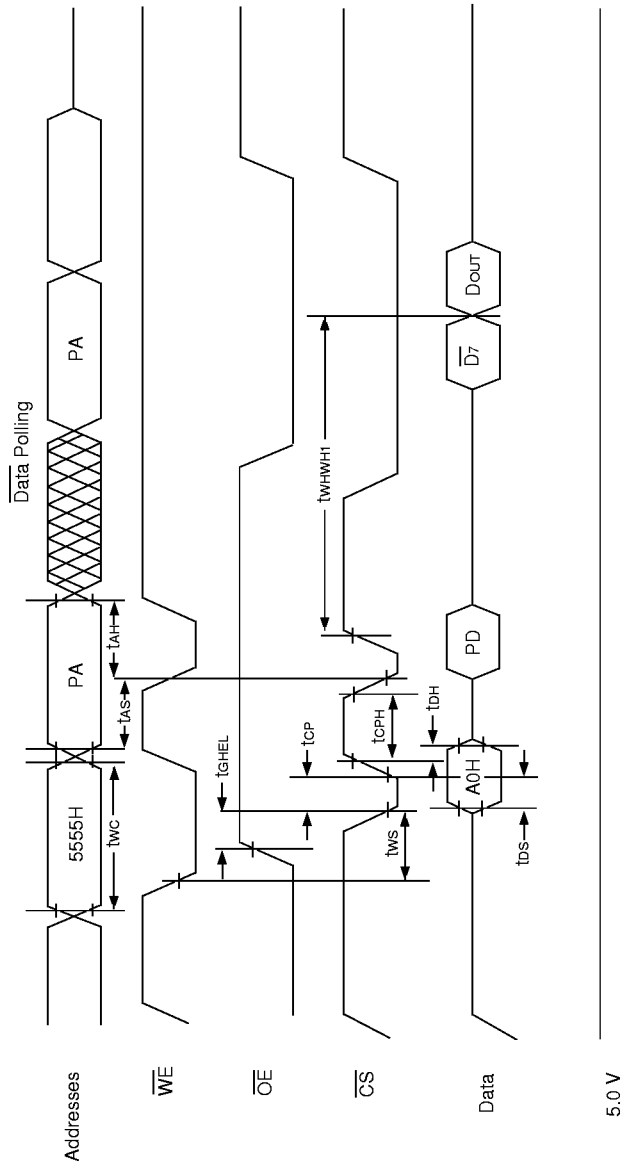




FIG. 7
WRITE/ERASE/PROGRAM OPERATION, \overline{CS} CONTROLLED

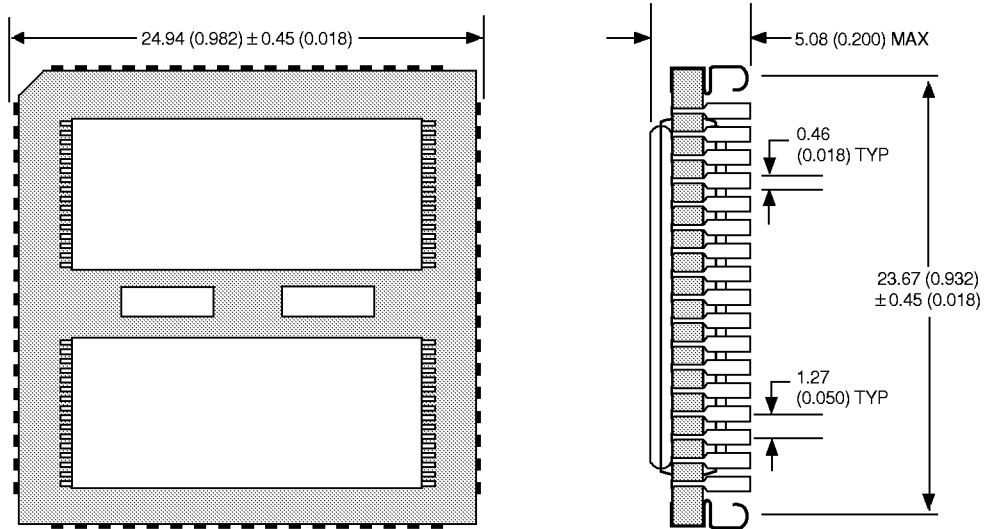


NOTES:

1. PA represents the address of the memory location to be programmed.
2. PD represents the data to be programmed at byte address.
3. $\overline{D7}$ is the output of the complement of the data written to the device.
4. DOUT is the output of the data written to the device.
5. Figure indicates the last two bus cycles of a four bus cycle sequence.



FIG. 8
PACKAGE DIMENSIONS



ALL LINEAR DIMENSIONS ARE MILLIMETERS AND PARENTHETICALLY IN INCHES

ORDERING INFORMATION

